

Edition 2.0 2021-02 REDLINE VERSION

INTERNATIONAL STANDARD



Terrestrial photovoltaic (PV) modules – Design qualification and type approval – Part 2: Test procedures

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IEC 61215-2:2021

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

TERRESTRIAL PHOTOVOLTAIC (PV) MODULES - DESIGN QUALIFICATION AND TYPE APPROVAL -

Part 2: Test procedures

FOREWORD

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This redline version of the official IEC Standard allows the user to identify the changes made to the previous edition IEC 61215-2:2016. A vertical bar appears in the margin wherever a change has been made. Additions are in green text, deletions are in strikethrough red text.

International Standard IEC 61215-2 has been prepared by IEC technical committee 82: Solar photovoltaic energy systems.

This second edition of IEC 61215-2 cancels and replaces the first edition of IEC 61215-2 issued in 2016; it constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) Addition of cyclic (dynamic) mechanical load testing (MQT 20).
- b) Addition of a test for detection of potential-induced degradation (MQT 21).
- c) Addition of test methods required for bifacial PV modules.
- d) Addition of test methods required for flexible modules. This includes the addition of the bending test (MQT 22).
- e) Revision of simulator requirements to ensure uncertainty is both well-defined and minimized.
- f) Correction to the hot spot endurance test, where the procedure for monolithically integrated (MLI) thin film technologies (MQT 09.2) previously included two sections describing a procedure only appropriate for silicon modules.
- g) Selection of three diodes, rather than all, for testing in the bypass diode thermal test (MQT 18).
- h) Removal of the nominal module operating test (NMOT), and associated test of performance at NMOT, from the IEC 61215 series.

Informative Annex A of IEC 61215-1:2021 explains the background and reasoning behind some of the more substantial changes that were made in the IEC 61215 series in progressing from edition 1 to edition 2.

The text of this standard is based on the following documents:

	FDIS IEC 6121	5_2 Report on voting
.ai/catalo	/stan 82/1829/FDIS 602 da	_b7b 82/1853/RVD_9e07

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 61215 series, published under the general title *Terrestrial photovoltaic (PV) modules – Design qualification and type approval*, can be found on the IEC website.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "http://webstore.iec.ch" in the data related to the specific document. At this date, the document will be

- · reconfirmed,
- withdrawn,
- · replaced by a revised edition, or
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INTRODUCTION

Whereas Part 1 of this standards series describes requirements (both in general and specific with respect to device technology), the sub-parts of Part 1 define technology variations and Part 2 defines a set of test procedures necessary for design qualification and type approval. The test procedures described in Part 2 are valid for all device technologies.

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TERRESTRIAL PHOTOVOLTAIC (PV) MODULES – DESIGN QUALIFICATION AND TYPE APPROVAL –

Part 2: Test procedures

1 Scope and object

This International Standard series lays down IEC requirements for the design qualification and type approval of terrestrial photovoltaic modules suitable for long-term operation in general open-air climates, as defined in IEC 60721-2-1. This part of IEC 61215 is intended to apply to all terrestrial flat plate module materials such as crystalline silicon module types as well as thin-film modules.

This document lays down requirements for the design qualification of terrestrial photovoltaic modules suitable for long-term operation in open-air climates. The useful service life of modules so qualified will depend on their design, their environment and the conditions under which they are operated. Test results are not construed as a quantitative prediction of module lifetime.

In climates where 98th percentile operating temperatures exceed 70 °C, users are recommended to consider testing to higher temperature test conditions as described in IEC TS 63126¹. Users desiring qualification of PV products with lesser lifetime expectations are recommended to consider testing designed for PV in consumer electronics, as described in IEC TS 63163 (under development). Users wishing to gain confidence that the characteristics tested in IEC 61215 appear consistently in a manufactured product may wish to utilize IEC 62941 regarding quality systems in PV manufacturing.

This document is intended to apply to all terrestrial flat plate module materials such as crystalline silicon module types as well as thin-film modules.

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This document does not apply to modules used with concentrated sunlight although it may be utilized for low concentrator modules (1 to 3 suns). For low concentration modules, all tests are performed using the irradiance, current, voltage and power levels expected at the design concentration.

The objective of this test sequence is to determine the electrical and thermal characteristics of the module and to show, as far as possible within reasonable constraints of cost and time, that the module is capable of withstanding prolonged exposure in general open-air climates. The actual lifetime expectancy of modules so qualified will depend on their design, their environment and the conditions under which they are operated.

The objective of this test sequence is to determine the electrical characteristics of the module and to show, as far as possible within reasonable constraints of cost and time, that the module is capable of withstanding prolonged exposure outdoors. Accelerated test conditions are empirically based on those necessary to reproduce selected observed field failures and are applied equally across module types. Acceleration factors may vary with product design and thus not all degradation mechanisms may manifest. Further general information on accelerated test methods including definitions of terms may be found in IEC 62506.

Some long-term degradation mechanisms can only reasonably be detected via component testing, due to long times required to produce the failure and necessity of stress conditions that are expensive to produce over large areas. Component tests that have reached a sufficient

Information on 98th percentile operating temperature as a function of system location and mounting configuration is included in IEC TS 63126.

level of maturity to set pass/fail criteria with high confidence are incorporated into the IEC 61215 series via addition to Table 1 in IEC 61215-1:2021. In contrast, the tests procedures described in this series, in IEC 61215-2, are performed on modules.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60050, International Electrotechnical Vocabulary (available at http://www.electropedia.org)

IEC 60068-1, Environmental testing - Part 1: General and guidance

IEC 60068-2-21, Environmental testing – Part 2-21: Tests – Test U: Robustness of terminations and integral mounting devices

IEC 60068-2-78:2012, Environmental testing – Part 2-78: Tests – Test Cab: Damp heat, steady state

IEC 60721-2-1, Classification of environmental conditions – Part 2-1: Environmental conditions appearing in nature – Temperature and humidity

IEC 60891, Photovoltaic devices – Procedures for temperature and irradiance corrections to measured I-V characteristics

IEC 60904-1, Photovoltaic devices – Part 1: Measurements of photovoltaic current-voltage characteristics

IEC 60904-1-1, Photovoltaic devices – Part 1-1: Measurement of current-voltage characteristics of multi-junction photovoltaic (PV) devices

IEC TS 60904-1-2, Photovoltaic devices – Part 1-2: Measurement of current-voltage characteristics of bifacial photovoltaic (PV) devices

IEC 60904-2, Photovoltaic devices – Part 2: Requirements for photovoltaic reference devices

IEC 60904-3, Photovoltaic devices – Part 3: Measurement principles for terrestrial photovoltaic (PV) solar devices with reference spectral irradiance data

IEC 60904-7, Photovoltaic devices – Part 7: Computation of the spectral mismatch correction for measurements of photovoltaic devices

IEC 60904-8, Photovoltaic devices – Part 8: Measurement of spectral responsivity of a photovoltaic (PV) device

IEC 60904-9:2020, Photovoltaic devices – Part 9: Classification of solar simulator-performance requirements characteristics

IEC 60904-10, Photovoltaic devices - Part 10: Methods of linearity measurement

IEC TR 60904-14: Photovoltaic devices – Part 14: Guidelines for production line measurements of single-junction PV module maximum power output and reporting at standard test conditions

IEC 61140, Protection against electric shock – Common aspects for installation and equipment

IEC 61215-1:2021, Terrestrial photovoltaic (PV) modules – Design qualification and type approval – Part 1: Test requirements

IEC 61215-1-1, Terrestrial photovoltaic (PV) modules – Design qualification and type approval – Part 1-1: Special requirements for testing of crystalline silicon photovoltaic (PV) modules

IEC 61730-1:2016, Photovoltaic (PV) module safety qualification – Part 1: Requirements for construction

IEC 61730-2, Photovoltaic (PV) module safety qualification – Part 2: Requirements for testing

IEC TS 61836, Solar photovoltaic energy systems – Terms, definitions and symbols

IEC 61853-2, Photovoltaic (PV) module performance testing and energy rating – Part 2: Spectral response, incidence angle, and module operating temperature measurements²

IEC TS 62782, Photovoltaic (PV) modules - Cyclic (dynamic) mechanical load testing

IEC 62790, Junction boxes for photovoltaic modules - Safety requirements and tests

IEC TS 62804-1:2015, Photovoltaic (PV) modules – Test methods for the detection of potential-induced degradation – Part 1: Crystalline silicon

IEC TS 63163: -3 Terrestrial photovoltaic (PV) modules for consumer products – Design qualification and type approval

ISO 868, Plastics and ebonite – Determination of indentation hardness by means of a durometer (Shore hardness)

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3 Terms and definitions

For the purposes of this document, the terms and definitions given in IEC 60050 and IEC TS 61836 and IEC 61215-1:2021 apply, as well as the following.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- IEC Electropedia: available at http://www.electropedia.org/
- ISO Online browsing platform: available at http://www.iso.org/obp

3.1

accuracy <of a measuring instrument>

quality which characterizes the ability of a measuring instrument to provide an indicated value close to a true value of the measurand [consistent with the International Vocabulary of Metrology (VIM), 5.18]

Note 1 to entry: This term is used in the "true value" approach.

Note 2 to entry: Accuracy is all the better when the indicated value is closer to the corresponding true value.

²—To be published.

Under preparation. Stage at the time of publication: ADTS.